

# **Quality and Reliability Technical Symposium 2015**

**(QRTS 2015)**

**Formerly CARTS**

**Mesa, Arizona, USA  
23-25 March 2015**

**ISBN: 978-1-5108-0322-0**

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Curran Associates, Inc.  
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Red Hook, NY 12571



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# QRTS 2015 Symposium

## Session 1 | Military/Aerospace

*AFRL Capacitor Test Measurements in Replicated Aircraft Environment;* 1  
Hiroyuki Kosai, UES Inc.

*Advances & Performance in Polymer Hermetic Seal (PHS) Ta Capacitors;* 12  
Yuri Freeman, KEMET Electronics

*Counterfeit Component Detection at Raytheon: Techniques, Examples and  
Statistical Results;* ~~AFJ~~  
Michael Cozzolino, Raytheon SAS

*Lower PM Content Metallization for Passive Component for Reliable Applications;* ~~AGI~~  
Doug Hargrove, Heraeus

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## Session 2 | Automotive Applications

*High Performance Axial Capacitors for Automotive Electronics;* ~~AAA~~ €  
Rong Xu, KEMET Electronics

*Complexities in the Thermal Modeling of Chip Resistors;* ~~AAA~~ H  
Amit Das, State of the Art, Inc.

*Random Vibration Testing of Advanced Wet Tantalum Capacitors;* ~~AAA~~ J  
Alexander Teverosky, ASRC

*Reliability of Tantalum Capacitors with Conductive Polymer and Manganese Dioxide Electrolytes under Thermal Cycling;* ~~AAA~~ I  
Anto Peter, CALCE, University of Maryland

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## Session 3 | Medical Applications

*HAST Testing of Aluminum Electrolytic Capacitors with Conductive Polymer Electrolytes; ~~AA~~ I*

Helmut Bevensee, CALCE, University of Maryland

*How to Design with a Programmable Switch; ~~AFCE~~*

Hassan Sajadi, NKK Switches

*Failure Analysis of Hi-CV miniature MLCC by Dual Beam FIB; ~~AFCE~~*

Kiyoshi Matsubara, KYOCERA Corporation

*Authorized Enhanced Testing vs. Independent Up-Screening – Quality of Test; ~~AFFI~~*

Gary Francoeur, Rochester Electronics

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## Session 4 | Energy Applications

*Hermetically Sealed Low ESR, High Reliability Ta Capacitors;* ~~ÁÉÉ~~  
Jan Petrzilek, AVX Czech Republic s.r.o.

*Resistor Selection for Pulse/Surge Applications;* ~~ÁÉÉ~~  
Tom Morris, TT electronics

*Reliability Factors and Failure Mechanism of a Deep Trench Silicon Capacitor;* ~~ÁÉÉ~~  
Catherine Brunel, IPDiA

*Tailoring the Microstructure: Optimization of Tantalum Powders for Highest Voltage Applications up to 350 V;* ~~ÁÉÉ~~  
Marcel Hagymasi, H.C. Starck GmbH

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